2-input NAND gate; open drain Rev. 1 — 27 November 2013

Product data sheet

General description 1.

The 74LVC1G38-Q100 provides a 2-input NAND function.

Inputs can be driven from either 3.3 V or 5 V devices. This feature allows the use of this device as translator in a mixed 3.3 V and 5 V environment.

This device is fully specified for partial power-down applications using IOFF. The IOFF circuitry disables the output, preventing the damaging backflow current through the device when it is powered down.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. **Features and benefits**

- Automotive product qualification in accordance with AEC-Q100 (Grade 1) Specified from –40 °C to +85 °C and from –40 °C to +125 °C
- Wide supply voltage range from 1.65 V to 5.5 V
- 5 V tolerant outputs for interfacing with 5 V logic
- High noise immunity
- Complies with JEDEC standard:
 - JESD8-7 (1.65 V to 1.95 V)
 - JESD8-5 (2.3 V to 2.7 V)
 - JESD8-B/JESD36 (2.7 V to 3.6 V).
- ± 24 mA output drive (V_{CC} = 3.0 V)
- CMOS low power consumption
- Open drain outputs
- Latch-up performance exceeds 250 mA
- Direct interface with TTL levels
- Inputs accept voltages up to 5 V
- ESD protection:
 - MIL-STD-883, method 3015 exceeds 2000 V
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V (C = 200 pF, R = 0 Ω)
- Multiple package options



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3. Ordering information

Table 1. Ordering information								
Type number	Package							
	Temperature range	Name	Description	Version				
74LVC1G38GW-Q100	–40 °C to +125 °C	TSSOP5	plastic thin shrink small outline package; 5 leads; body width 1.25 mm	SOT353-1				
74LVC1G38GV-Q100	–40 °C to +125 °C	SC-74A	plastic surface-mounted package; 5 leads	SOT753				

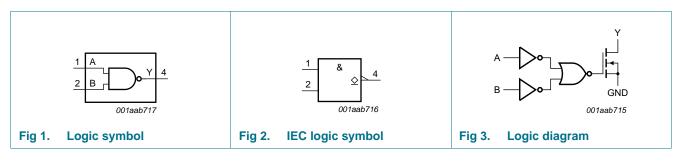
4. Marking

Table	2.	Marking

Type number	Marking code ^[1]
74LVC1G38GW-Q100	YB
74LVC1G38GV-Q100	YB

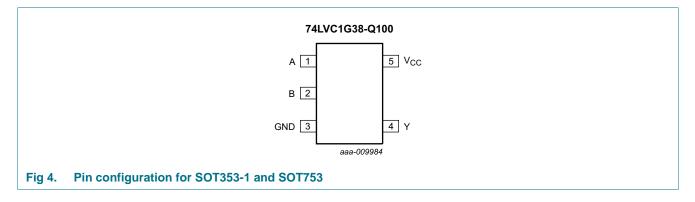
[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

5. Functional diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3.	Pin description	
Symbol	Pin	Description
A	1	data input
В	2	data input
GND	3	ground (0 V)
Y	4	data output
V _{CC}	5	supply voltage

7. Functional description

Table 4. Function table^[1]

Input		Output
Α	В	Y
L	L	Z
L	Н	Z
Н	L	Z
Н	Н	L

[1] H = HIGH voltage level; L = LOW voltage level; Z = high-impedance OFF state.

8. Limiting values

Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

					,
Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+6.5	V
I _{IK}	input clamping current	V _I < 0 V	-50	-	mA
VI	input voltage		<u>[1]</u> –0.5	+6.5	V
I _{OK}	output clamping current	$V_{\rm O}$ > $V_{\rm CC}$ or $V_{\rm O}$ < 0 V	-	±50	mA
Vo	output voltage	Active mode	[1][2] -0.5	+6.5	V
		Power-down mode	[1][2] -0.5	+6.5	V
lo	output current	$V_{O} = 0 V$ to V_{CC}	-	±50	mA
I _{CC}	supply current		-	100	mA
I _{GND}	ground current		-100	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 \text{ °C to } +125 \text{ °C}$	<u>[3]</u> _	300	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] When $V_{CC} = 0 V$ (Power-down mode), the output voltage can be 5.5 V in normal operation.

[3] For TSSOP5 and SC-74A packages: above 87.5 °C the value of Ptot derates linearly with 4.0 mW/K.

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9. Recommended operating conditions

Table 6.	Recommended operating	ng conditions				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage		1.65	-	5.5	V
VI	input voltage		0	-	5.5	V
Vo	output voltage	Active mode	0	-	5.5	V
		Disable mode; V_{CC} = 1.65 V to 5.5 V	0	-	5.5	V
		Power-down mode; $V_{CC} = 0 V$	0	-	5.5	V
T _{amb}	ambient temperature		-40	-	+125	°C
$\Delta t / \Delta V$	input transition rise and	V_{CC} = 1.65 V to 2.7 V	-	-	20	ns/V
	fall rate	$V_{CC} = 2.7 \text{ V to } 5.5 \text{ V}$	-	-	10	ns/V

10. Static characteristics

Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
T _{amb} = -	40 °C to +85 °C <u>[1]</u>					
V _{IH}	HIGH-level input voltage	$V_{CC} = 1.65 \text{ V} \text{ to } 1.95 \text{ V}$	$0.65V_{CC}$	-	-	V
		V_{CC} = 2.3 V to 2.7 V	1.7	-	-	V
		$V_{CC} = 2.7 V \text{ to } 3.6 V$	2.0	-	-	V
		V_{CC} = 4.5 V to 5.5 V	$0.7V_{CC}$	-	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 1.65 V to 1.95 V	-	-	$0.35V_{CC}$	V
		V_{CC} = 2.3 V to 2.7 V	-	-	0.7	V
		$V_{CC} = 2.7 V \text{ to } 3.6 V$	-	-	0.8	V
		V_{CC} = 4.5 V to 5.5 V	-	-	$0.3V_{CC}$	V
V _{OL}	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$	-	-	-	
		I_O = 100 $\mu A;V_{CC}$ = 1.65 V to 5.5 V	-	-	0.1	V
		$I_{O} = 4 \text{ mA}; V_{CC} = 1.65 \text{ V}$	-	-	0.45	V
		$I_{O} = 8 \text{ mA}; V_{CC} = 2.3 \text{ V}$	-	-	0.3	V
		I_{O} = 12 mA; V_{CC} = 2.7 V	-	-	0.4	V
		$I_{O} = 24 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.55	V
		$I_{O} = 32 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	-	0.55	V
I _I	input leakage current	V _I = 5.5 V or GND; V _{CC} = 0 V to 5.5 V	-	±0.1	±5	μA
I _{OZ}	OFF-state output current	$ V_{I} = V_{IH} \text{ or } V_{IL}; V_{O} = V_{CC} \text{ or } GND; $	-	±0.1	±10	μA
I _{OFF}	power-off leakage current	$V_{I} \text{ or } V_{O} = 5.5 \text{ V}; V_{CC} = 0 \text{ V}$	-	±0.1	±10	μA
I _{CC}	supply current	$V_{I} = 5.5 V \text{ or GND};$ $V_{CC} = 1.65 V \text{ to } 5.5 V; I_{O} = 0 A$	-	0.1	10	μA
Δl _{CC}	additional supply current	$V_{I} = V_{CC} - 0.6 V; I_{O} = 0 A;$ $V_{CC} = 2.3 V to 5.5 V; per pin$	-	5	500	μΑ
CI	input capacitance		-	2.5	-	pF

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
T _{amb} = –	40 °C to +125 °C					
VIH	HIGH-level input voltage	V _{CC} = 1.65 V to 1.95 V	$0.65V_{CC}$	-	-	V
		V_{CC} = 2.3 V to 2.7 V	1.7	-	-	V
		V_{CC} = 2.7 V to 3.6 V	2.0	-	-	V
		V_{CC} = 4.5 V to 5.5 V	$0.7V_{CC}$	-	-	V
V _{IL}	LOW-level input voltage	V_{CC} = 1.65 V to 1.95 V	-	-	$0.35V_{CC}$	V
		V_{CC} = 2.3 V to 2.7 V	-	-	0.7	V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	-	-	0.8	V
		V_{CC} = 4.5 V to 5.5 V	-	-	$0.3V_{CC}$	V
V _{OL}	LOW-level output voltage	$V_{I} = V_{IH} \text{ or } V_{IL}$	-	-	-	
		I_{O} = 100 $\mu\text{A};$ V_{CC} = 1.65 V to 5.5 V	-	-	0.1	V
		I _O = 4 mA; V _{CC} = 1.65 V	-	-	0.70	V
		$I_0 = 8 \text{ mA}; V_{CC} = 2.3 \text{ V}$	-	-	0.45	V
		$I_0 = 12 \text{ mA}; V_{CC} = 2.7 \text{ V}$	-	-	0.60	V
		$I_0 = 24 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.80	V
		$I_0 = 32 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	-	0.80	V
I	input leakage current	V _I = 5.5 V or GND; V _{CC} = 0 V to 5.5 V	-	-	±100	μΑ
I _{OZ}	OFF-state output current		-	-	±200	μA
I _{OFF}	power-off leakage current	$V_1 \text{ or } V_0 = 5.5 \text{ V}; V_{CC} = 0 \text{ V}$	-	-	±200	μA
I _{CC}	supply current	$V_{I} = 5.5 V \text{ or GND};$ $V_{CC} = 1.65 V \text{ to } 5.5 V; I_{O} = 0 \text{ A}$	-	-	200	μΑ
∆l _{CC}	additional supply current	$V_{I} = V_{CC} - 0.6 V$; $I_{O} = 0 A$; $V_{CC} = 2.3 V$ to 5.5 V; per pin	-	-	5000	μA

Table 7. Static characteristics ...continued

[1] All typical values are measured at V_{CC} = 3.3 V and T_{amb} = 25 °C.

11. Dynamic characteristics

Table 8.Dynamic characteristics

Voltages are referenced to GND (ground = 0 V); for test circuit see <u>Figure 6</u>.

Symbol	Parameter	Conditions	Conditions -40 °C to +85 °C		Conditions -40 °C to +85 °C -40 °C to +125 °C			o +125 ℃	Unit
			Min	Typ <mark>[1]</mark>	Max	Min	Max		
t _{pd} propagation delay		A, B to Y; see Figure 5							
	V_{CC} = 1.65 V to 1.95 V	1.0	3.0	10.0	1.0	12.5	ns		
	V_{CC} = 2.3 V to 2.7 V	0.5	1.8	6.0	0.5	7.5	ns		
	$V_{CC} = 2.7 V$	0.5	2.5	5.0	0.5	6.5	ns		
		$V_{CC} = 3.0 \text{ V} \text{ to } 3.6 \text{ V}$	0.5	2.3	4.5	0.5	5.7	ns	
		V_{CC} = 4.5 V to 5.5 V	0.5	1.5	3.9	0.5	4.9	ns	

Voltages	Voltages are referenced to GND (ground = 0 V); for test circuit see <u>Figure 6</u> .								
Symbol	Parameter	Conditions40 °C to +85 °C40 °C to +125 °C		–40 °C to +85 °C			• +125 °C	Unit	
				Min	Typ[1]	Max	Min	Max	
C_{PD}	power dissipation capacitance	$V_{CC} = 3.3 \text{ V};$ $V_{I} = \text{GND to } V_{CC}$	[3]	-	6	-	-	-	pF

Table 8. Dynamic characteristics ... continued

[1] Typical values are measured at T_{amb} = 25 °C and V_{CC} = 1.8 V, 2.5 V, 2.7 V, 3.3 V and 5.0 V respectively.

[2] t_{pd} is the same as t_{PZL} and t_{PLZ} .

[3] C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} \times N + \sum (C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$

 f_i = input frequency in MHz;

 $f_o = output frequency in MHz;$

C_L = output load capacitance in pF;

 V_{CC} = supply voltage in V;

N = number of inputs switching;

 $\sum (C_L \times V_{CC}^2 \times f_o) = sum of outputs.$

12. Waveform and test circuit

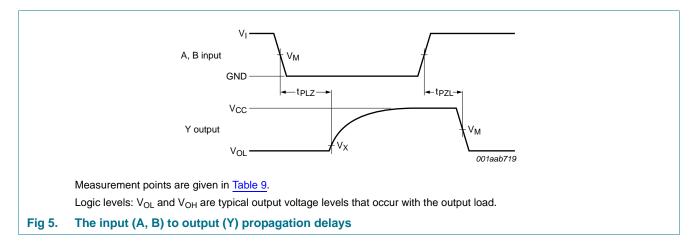


Table 9. **Measurement points**

Supply voltage	Input	Output	
V _{cc}	V _M	V _M	V _X
1.65 V to 1.95 V	0.5V _{CC}	0.5V _{CC}	V _{OL} + 0.15 V
2.3 V to 2.7 V	0.5V _{CC}	0.5V _{CC}	V _{OL} + 0.15 V
2.7 V	1.5 V	1.5 V	V _{OL} + 0.3 V
3.0 V to 3.6 V	1.5 V	1.5 V	V _{OL} + 0.3 V
4.5 V to 5.5 V	0.5V _{CC}	0.5V _{CC}	V _{OL} + 0.3 V

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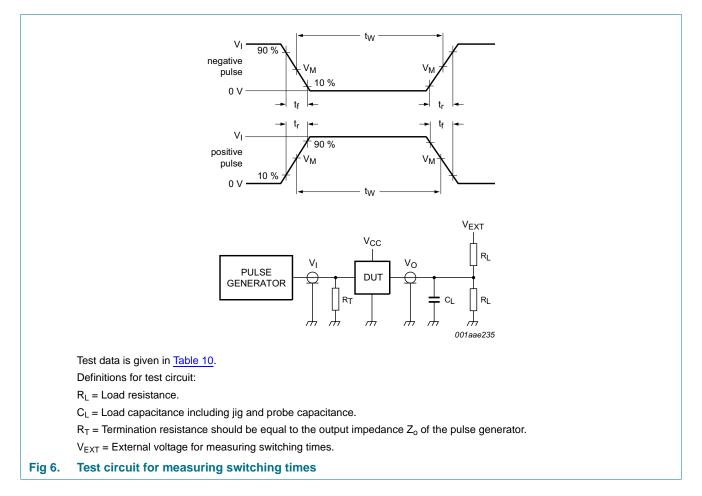


Table 10. Test data

Supply voltage	Input		Load	Load	
V _{cc}	VI	t _r , t _f	CL	RL	t _{PZL} , t _{PLZ}
1.65 V to 1.95 V	V _{CC}	\leq 2.0 ns	30 pF	1 kΩ	V _{CC}
2.3 V to 2.7 V	V _{CC}	\leq 2.0 ns	30 pF	500 Ω	V _{CC}
2.7 V	2.7 V	\leq 2.5 ns	50 pF	500 Ω	V _{CC}
3.0 V to 3.6 V	2.7 V	\leq 2.5 ns	50 pF	500 Ω	V _{CC}
4.5 V to 5.5 V	V _{CC}	≤ 2.5 ns	50 pF	500 Ω	V _{CC}

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13. Package outline

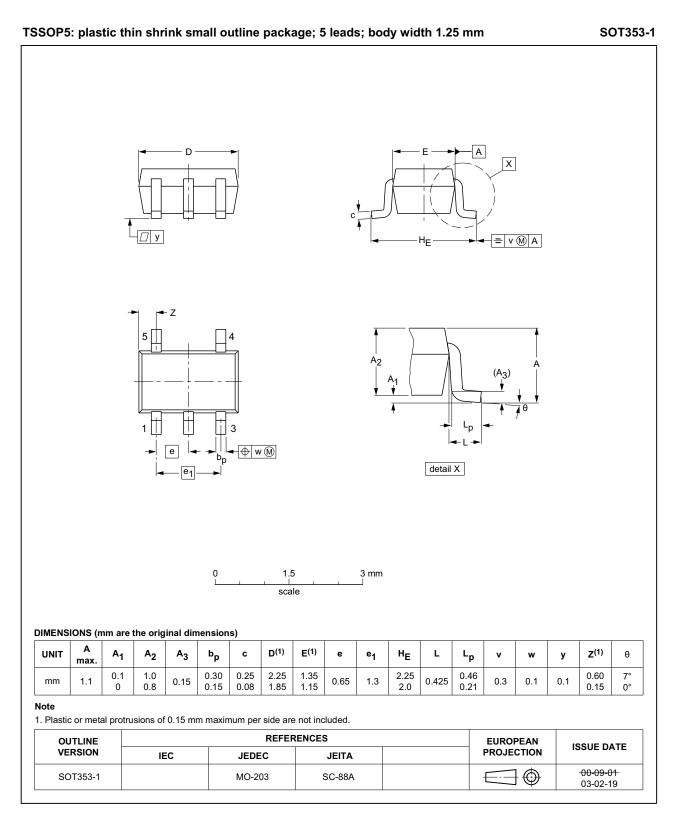


Fig 7. Package outline SOT353-1 (TSSOP5)

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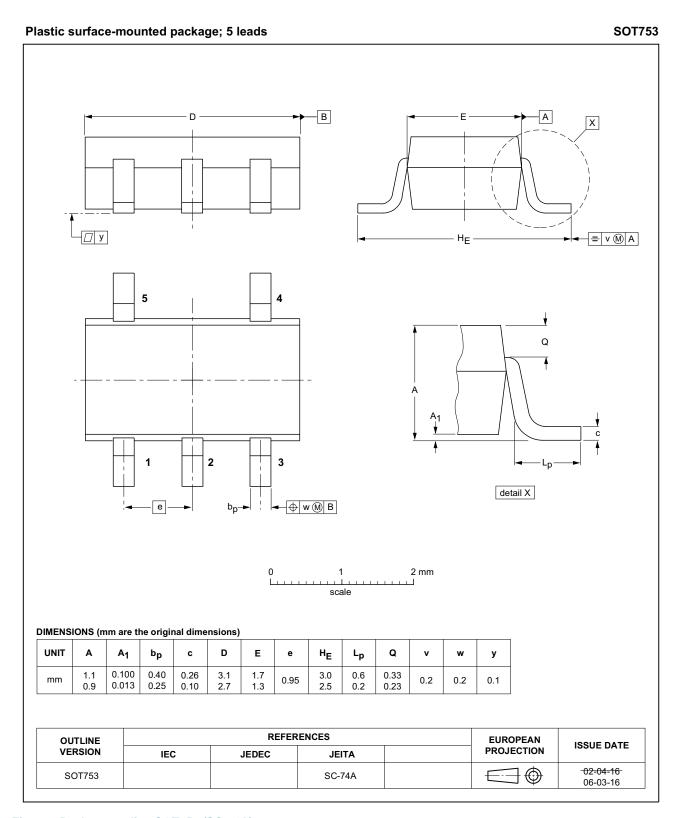


Fig 8. Package outline SOT753 (SC-74A)

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14. Abbreviations

Acronym	
···· , ···	Description
CMOS	Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MIL	Military
MM	Machine Model
TTL	Transistor-Transistor Logic

15. Revision history

Table 12. Revision hi	able 12. Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
74LVC1G38_Q100 v.1	20131127	Product data sheet	-	-	

16. Legal information

16.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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